

Search Notes**Application/Control No.**

10/817,417

Examiner

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Applicant(s)/Patent under Reexamination

YUE ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	706	12/20/2005	KCC
	714		
	715		
438	723		
216	63		
216	74	12/20/05	kcc

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

Exact Key words search
USPAT, USPTO, publ.
EP, JP, IBM TDB
Derwent, inventor search

12/20/2005

KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner